

DATA BUFFER

DESCRIPTION

The VL82C332 Data Buffer is part of a custom, three chip set which allows extremely high performance and integration in 386DX processor based, PC/AT®-compatible, personal computer designs. When used with VLSI Technology's VL82C330 System Controller and VL82C331 ISA Bus Controller, the set is called the VL82C386 chip set.

The VL82C332 performs all of the data buffering functions required for a 386DX-based PC/AT-type system. Under the control of the CPU, the Data Buffer chip routes data to and from the CPU bus, the MD bus, the XD bus, and the slots (SD bus). For an on-board DRAM read, the data is latched in the MD latch allowing the VL82C330 System Controller to be programmed for early CAS terminations. The parity

is checked for MD bus read operations and any errors are reported during the next on-board memory read cycle. When reading from ROM, the XD bus or the SD bus, the data can be converted from 8-bits wide to 16-, 24- or 32-bits wide or from 16 bits to 32 bits at the 16/32 latch. The data is latched with –LATLO and –LATHI for synchronization with the CPU. The data conversion is accomplished without the use of the bus size 16 (–BS16) input to the 386DX allowing it to remain in pipelined mode.

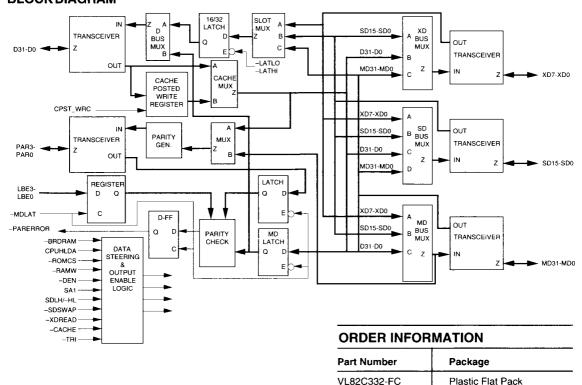
CPU writes to any of the three buses are accomplished in several different ways. The VL82C332 supports posted writes from a Cache Controller or non-posted writes to the MD bus. Parity is generated for all data written to the MD bus. The VL82C332 provides the data conversion necessary for 32- or 16-bit

writes to 16- or 8-bit devices on the XD or SD buses.

In non-cached systems, system board DRAM can be placed on the CPU's D bus. This provides extra timing margin when the MD bus delay through the VL82C332 is removed from the critical path.

Under the control of DMA or a Bus Master, the VL82C332 will allow 8- or 16-bit data to be routed to and from the XD and the MD buses. The chip also is capable of performing high-to-low and low-to-high byte swaps on the SD bus. For transfers between two peripherals on the slot bus, the outputs of the VL82C332 will be disabled. The chip also provides the feature of a single input, —TRI, to disable all of its outputs for board level testability.

BLOCK DIAGRAM



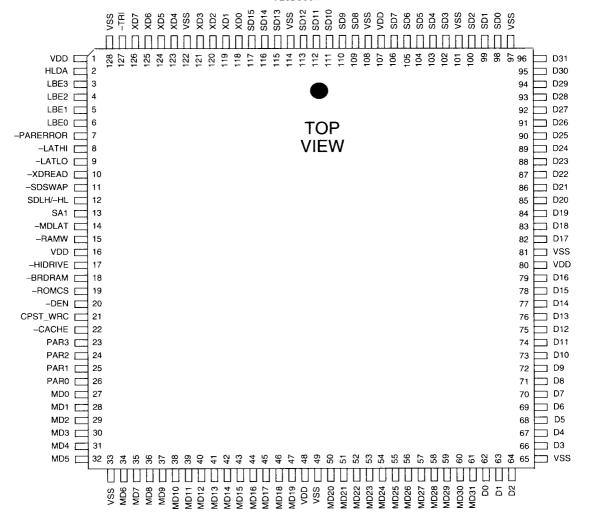
PC/AT is a register trademark of IBM Corp.

Note: Operating temperature range is 0°C to +70°C.



PIN DIAGRAM







ADVANCE INFORMATION

SIGNAL DESCRIPTIONS

Signal Name	Pin Number	Signal Type	Signal Description
CPU INTERFAC	CE	`	
HLDA	2	I-TTL	CPU Hold Acknowledge, active high - This is the hold acknowledge pin directly from the CPU. It indicates the CPU has given up the bus for either a DMA Master or a Slot Bus Master. It is used in the steering logic to determine data routing.
D31-D0	96-82, 79-66, 64-62	IO-TTL	CPU Data Bus - This is the data bus directly connected to the CPU. It is also referred to as the local data bus. This bus is output enabled by the –DEN signal.
CACHE INTERI	FACE		
CPST_WRC	21	I-TTL	Posted Cache Write Clock - This clock signal is driven by the Cache Controller and is needed to latch the write data during a posted cache write cycle. The data is latched on the rising edge of this signal. The latch inside of the Data Buffer is bypassed if the -CACHE input is high. Also, when -CACHE is high, the state of CPST_WRC determines on which bus (D or MD) system DRAM is accessed. When high, DRAM is accessed on the D bus. When low, DRAM is accessed on the MD bus.
-CACHE	22	I-TPU	Cache Enable, active low - This signal is used to enable the cache posted write register. When there is not a cache in the system, data bypasses the register. When –CACHE is inactive (high) the state of the CPST_WRC pin determines whether the system DRAM is on the CPU's D bus or on the MD bus.
SYSTEM CONT	ROLLER INTER	FACE	
-MDLAT	14	I-∏L	Memory Data Latch - This latching signal serves two purposes simultaneously and is only activated during on-board memory read and write cycles. As a memory data latch, this transparent low signal allows read data to flow through to the CPU's local bus. As a parity clock, it samples the byte enables, –RAMW, and parity bits to be used for parity checking. Any parity errors will be reported on the next on-board memory read cycle.
-RAMW	15	I-TTL	RAM Write, active low - This signal is supplied by the System Controller to indicate that a memory write cycle is occurring. It is used internally to direct the parity logic and to enable the MD bus outputs.
-ROMCS	19	I-TTL	ROM Chip Select - This signal tells the Data Buffer when the ROM is to be accessed so that it can latch the data and convert it from 16 or 8 bits to 32 bits. This signal is driven by the System Controller.
-BRDRAM	18	I-TTL	Board Memory Selected, active low - This signal is driven by the System Controller and indicates when on-board DRAM is being accessed.
-DEN	20	I-TTL	Data Enable, active low - This is a control signal generated by the System Controller. It is used as an output enable for the D bus.
LBE3-LBE0	3-6	I-TTL	Latch Byte Enables 3 through 0 - These signals are driven by the System Controller. They are used internally to enable the appropriate bytes for parity checking.
-PARERROR	7	0	Parity Error, active low - This signal is the result of a parity check on the appropriate bytes being read from memory. It is generated on the falling edge of –MDLAT.
BUS CONTROL	LLER INTERFAC	E	
SA1	13	I-TTL	System Address Bus bit 1 - This input will be driven by the Bus Controller or by the controlling DMA or Bus Master. This signal is used for 16- to 32-bit conversion. When low, this signal indicates the low word is to be used.

SIGNAL DESCRIPTIONS (Cont.)

Signal Name	Pin Number	Signal Type	Signal Description
SDLH/-HL	12	I-TTL	System Data Bus Low-to-High/High-to-Low Swap - This signal is driven by the Bus Controller. It is used to establish the direction of byte swaps.
-SDSWAP	11	I-TTL	System Data Bus Byte Swap Enable, active low - This signal is driven by the Bus Controller. It is the qualifying signal needed for SDLH/–HL.
-XDREAD	10	I-TTL	Peripheral Data Bus (XD Bus) Read, active low - This signal is driven by the Bus Controller and it determines the direction of the XD bus data flow. When this signal is high, the XD Bus is output enabled.
–LATHI	8	I-TTL	High Byte Latch - This signal is needed to latch the high byte to the local data bus until the CPU is ready to sample the bus. When SA1 is low, the high byte is latched into both the 1 byte and the 3 byte of the 16/32 latch. When SA1 is high, the high byte is only latched into the 3 byte. This signal is driven by the Bus Controller.
-LATLO	9	I-TTL	Low Byte Latch - This signal is needed to latch the low byte to the local data bus until the CPU is ready to sample the bus. When SA1 is low, the low byte is latched into both the 0 byte and the 2 byte of the 16/32 latch. When SA1 is high, the high byte is only latched into the 2 byte. This signal is driven by the Bus Controller.
BUFFER INTE		IO TTI	Manager Data Dura. This has accepted to the on heard DDAM and DIOC
MD31-MD0	61-50, 47-34, 32-27	IO-TTL	Memory Data Bus - This bus connects to the on-board DRAM and BIOS ROM. It is used to transfer data to/from memory during memory write/read bus cycles.
SD15-SD0	117-115, 103-109, 106-102, 100-98	IO-TTL	System Data Bus - This bus connects directly to the slots. It is used to transfer data to/from local and system devices.
XD7-XD0	126-123, 121-118	IO-TTL	Peripheral Data Bus - This bus is connected to the Bus Controller and the System Controller. These I/O's are used to read and write to on-board 8-bit peripherals.
PAR3-PAR0	23-26	IO-TTL	Parity Bits 3 through 0 - These bits are generated by the parity generation circuitry located on the Data Buffer chip. They are written to memory along with their corresponding bytes during memory write operations. During memory read operations, these bits become inputs and are used along with their respective data bytes to determine if a parity error has occurred. The check of each byte is enabled only when their respective LBE3-LBE0 bits are active.
-HIDRIVE	17	I-TPU	High Drive Enable - This pin is a wire option. When this pin is low, the SD bus will sink 24 mA of current. When this pin is high, the SD bus will sink 12 mA.
TEST MODE P			
-TRI	127	I-TPU	Three-state - This pin is used to drive all outputs to a high impedance state. When –TRI is low, all outputs and bidirectional pins are three-stated.
	CONNECTION	DWD	Down connection pominally (5 yells. These pine should each have 0.4
VDD	1, 16. 48, 80, 107	PWR	Power connection, nominally +5 volts. These pins should each have 0.1 μF bypass capacitors.
VSS	33, 49, 65, 81, 97, 101, 108, 114, 122, 126	GND	Ground connection, 0 volts.



SIGNAL TYPE LEGEND

Signal Code	Signal Type
I-TTL	TTL level input
I-TPU	Input with 30k ohm pull-up resistor
IO-TTL	TTL level input/ouput
0	CMOS and TTL level compatible output
GND	Ground
PWR	Power

FUNCTIONAL DESCRIPTION BUS OPERATIONS

The VL82C332 Data Buffer separates the data bus into four distinct buses:

- D bus
- MD bus.
- SD bus, and
- XD bus.

The D bus is the CPU's data bus. The MD bus is the memory data bus which connects to the on-board DRAM and the BIOS ROM. The SD bus is the 16-bit slot bus and the XD bus is an 8-bit bus for on-board peripherals such as the VL82C330 System Controller and the VL82C331 Bus Controller. These buses can be controlled by either the CPU, a DMA Controller or a Bus Master. Tables 1 and 2 show all possible bus steering modes provided by the VL82C332.

CACHE CONTROLLER INTERFACE

The cache controller interface is made up of a 32-bit register and a 64-to-32 MUX as shown in the block diagram. When a Cache Controller is not imple-

mented, the -CACHE input pin should be tied high. This will set the MUX such that the cache posted write register is bypassed. When a cache is implemented, -CACHE should be tied low and the CPST_WRC input is used to post the write data into the register. The register latches data on the rising edge of the CPST_WRC input.

MD, D Bus System DRAM Selection When the –CACHE input pin is tied low, system DRAM must be on the MD bus. However, when –CACHE is tied high, system DRAM may be placed on the MD bus or the CPU's D bus. The selection is made by the state of CPST_WRC. When tied low, DRAM is on the MD bus. When CPST_WRC is tied high, system DRAM is on the D bus. Since system board bus selection is hardwired on the system board, these pins can not be dynamically controlled in non-cache systems. They must be permanently tied to the proper level.

PARITY GENERATION AND DETECTION CIRCUIT

The parity check portion of the chip checks the parity of all data read from the on-board DRAM. During a DRAM read cycle, —MDLAT goes low making the MD latch transparent and latching out the parity check result, for the previous on-board memory read cycle. When —MDLAT returns high, data is latched into the MD latch. The parity check uses the Latched Byte Enable (LBE) signals from the System Controller to qualify each byte of the 32-bit word.

The parity generator provides parity generation for both CPU and DMA/Master writes to on-board DRAM. A 64 to 32 MUX is used to select whether the input to the parity generator is from the CPU or from a DMA/Master transfer. The result is output as one bit per data byte on the PAR3-PAR0 pins.



TABLE 1. BUS STATES WHEN PIN 21 = GROUND

Bus states for DRAM on the MD bus, ROM on the MD bus. Cache posted writes are supported.

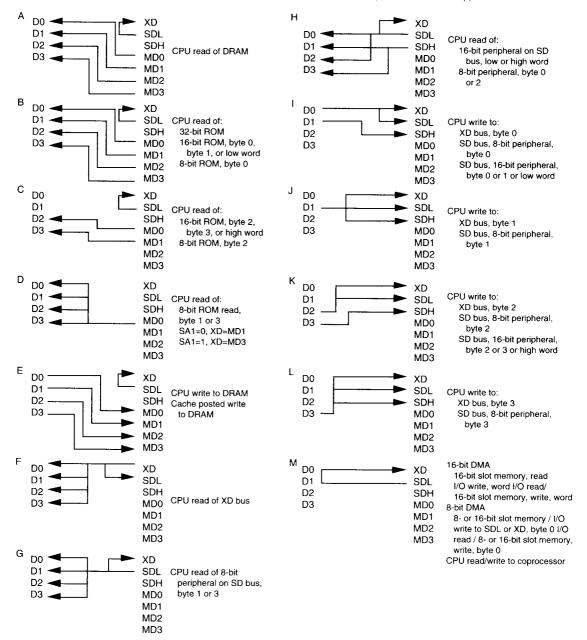




TABLE 1. BUS STATES WHEN PIN 21 = GROUND (Cont.)

Bus states for DRAM on the MD bus, ROM on the MD bus. Cache posted writes are supported.

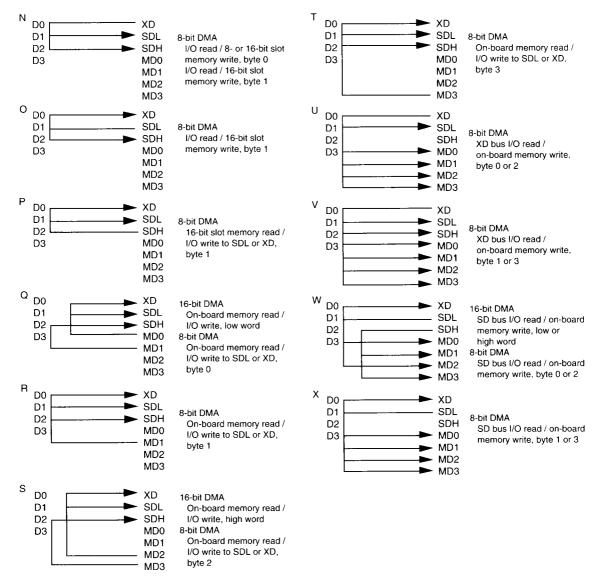




TABLE 2. BUS STATES WHEN PIN 21 = VDD

Bus states for DRAM on the D bus, ROM on the MD bus. Cache posted writes are not supported.

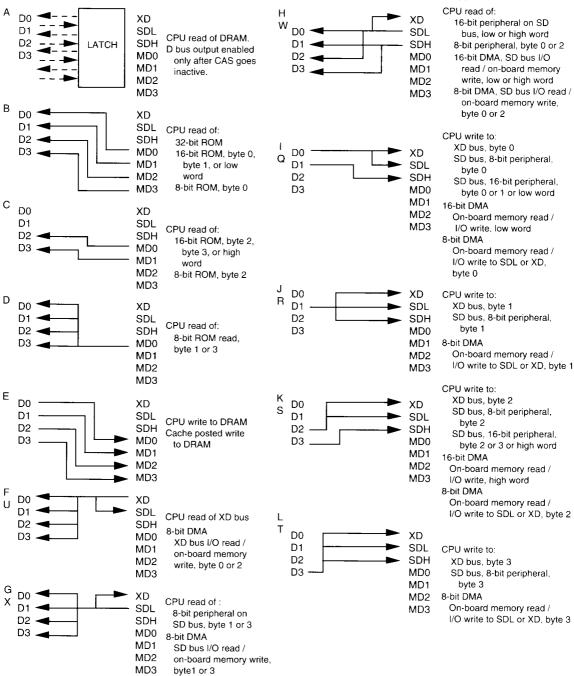
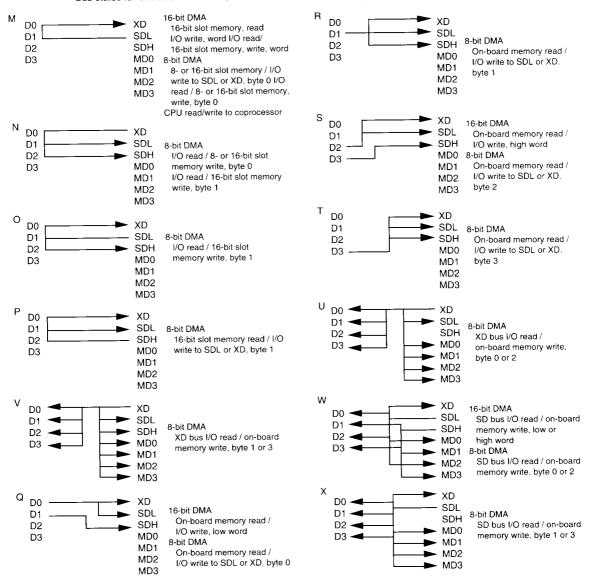




TABLE 2. BUS STATES WHEN PIN 21 = VDD (Cont.)

Bus states for DRAM on the D bus, ROM on the MD bus. Cache posted writes are not supported.





IN-CIRCUIT TESTING

ICT mode is not enabled in the current VL82C332 production parts. Since the VL82C332 is basically a matrix of multiplexers and I/O drivers, it is still possible to perform In-Circuit Test by application of an appropriate set of test vectors. This method is described below.

Future versions of the VL82C332 may have a true ICT mode. If so, the method described below may still be used as an option.

The values on the bidirectional buses are indicated as outputs by **boldface**

type. They are inputs, otherwise. This distinction is used to tell whether to drive the indicated value on the bus or read it from the bus. A value of "u" indicates an output that is still "unknown".

BLOCK 1 -

	s states A, C and I BUS (HI, LO),	D, and tests the f D BUS (HI,		g:	IBEE	BUS (H	I I O)	_D	ARERROR	(HL 10)	MDLA	T (HI, LO),
	MCS (HI, LO)	-BRDRAM)			HI, LO)		AMW (HI)	(III, LO),	-DEN (I	
\vee	M	D	S	S	Х	P	L	C		H	-SS-	_
Ε	D	:	D	D	D	А	В	THCP	PMLL	LDRB	RADS	Χ
С	:	:	Н	L	:	R	Ε	RIAS	ADAA	DEAR	OllD	D
\mathbf{T}	:	:	:	:	:	:	:	IDCT	RLTT	ANMD	M:HS	R
0	:	:	:	:	:	:	:	:RH_	EALH	::WR	C:/W	E
R	:	:	:	:	:	:	:	:IEW	RTOI	:::A	S:-A	А
	:	:	:	:	:	:	:	:V:R	R:::	:::M	::HP	D
#	:	:	:	:	:	:	:	:E:C	0:::	::::	::L:	:
	: 7	: -	:[:□	:□	:□	:П	::::	R:::	::::	::::	:
	TE A: VERIFY TI											
1 2	13579BDF	uuuuuuuu	00	00	00	0	8	1010	u111	0010	1011	1
	13579BDF	13579BDF	00	00	00	8	8	1010	u011	0010	1011	1
	TE A: LATCH IN			-		_						
3	13579BDF	13579BDF	00	00	00	8	4	1010	u111	0010	1011	1
4	13579BDF	13579BDF	00	00	00	4	4	1010	0011	0010	1011	1
	TE A: LATCH IN											
5	13579BDF	13579BDF	00	00	00	4	2	1010	0111	0010	1011	1
6	13579BDF	13579BDF	00	00	00	2	2	1010	0011	0010	1011	1
	TE A: LATCH IN	PARITY ERROF	ONB	YTE 1.								
7	13579BDF	13579BDF	00	00	00	2	1	1010	0111	0010	1011	1
8	13579BDF	13579BDF	00	00	00	1	1	1010	0011	0010	1011	1
	TE A: LATCH IN		ONB	YTE 0.								
9	13579BDF	13579BDF	00	0.0	00	1	0	1010	0111	0010	1011	1
10	13579BDF	13579BDF	00	00	00	0	0	1010	0011	0010	1011	1
	TE A: LATCH IN	GOOD PARITY	ON AL	L BYTE	ES.							
11	13579BDF	13579BDF	00	00	00	0	F	1010	0111	0010	1011	1
12	13579BDF	13579BDF	00	00	00	0	F	1010	1011	0010	1011	1
13	13579BDF	13579BDF	00	00	00	0	F	1010	1111	0010	1011	1
STAT	TE A: CHANGE N	ID BUS AND SE	E THA	T D BU	S DOE	S NOT	CHAN	GE.				
14	FDB97531	13579BDF	00	00	00	0	F	1010	1111	0010	1011	1
STAT	TE D: -ROMCS A	ND SDLH/-HL E	SYTE C	F MD I	BUS G	ото А	ALL BY	TES OF D	BUS.			
15	FDB97531	31313131	00	00	75	0	F	1010	1100	0011	0000	1
STAT	E C: RAISE SDL	.H/-HL, BYTES	1, 0 OF	MD B	us Go	то в	YTES 3.	2 OF D B	US.			
16	FDB97531	75313131	0.0	00	00	0	F	1010	1100	0011	0010	1
<u>17</u>	FDB97531	75313131	0.0	0.0	00	0	F	1010	1111	0011	0010	1



	OCK 2 -											
SDH	states F, G and F BUS (HI, LO) (HI, LO)	ł, and tests the fol SDL BUS (H –SDSWAP (I	I, LO)			US (HI READ(H	, LO) HI, LO)		LO (HI, LO A (LO)) –LA	THI (HI, LO	O)
V	M	D	S	S	Χ	P	L	C		H	-SS-	_
E	D	:	D	D	D	А	В	THCP	PMLL	LDRB	RADS	Х
С	:	:	Н	L	:	R	Ε	RIAS	ADAA	DEAR	O1LD	D
T	:	:	:	:	:	:	:	IDCT	RLTT	ANMD	M:HS	R
0	:	:	:	:	:	:	:	:RH_	EALH	::WR	C:/W	Ε
R	:	:	:	:	:	:	:	:IEW	RTOI	:::A	S:-A	А
	:	:	:	:	:	:	:	:V:R	R:::	:::M	::HP	D
#	:	:	:	:	:	:	:	:E:C	0:::	::::	::L:	:
	 		ĖТ	ĖΠ	:	·	. —	::::	R:::	::::	::::	:
18	FFFFFFF	AA55AA55	AA	55	55	0	F	1010	1100	0011	1011	1
19	FFFFFFFF	55 AA 55 A A	55	AA	AA	0	F	1010	1100	0011	1011	1
STA	TE H: FORCE -L	ATLO, –LATHI A	ND SA	1 HIG	H.							
20	FFFFFFFF	55AA55AA	55	AA	AA	0	F	1010	1111	0011	1111	1
STA	TE H: CHANGE	SD BUSES. D BU	JS SHO	ULD	NOT C	HANG	iΕ.					
21	FFFFFFF	55 AA 55 AA	33	CC	CC	0	F	1010	1111	0011	1111	1
STA	TE H: FORCE LA	ATLO AND LATH	I LOW.	TWC	HIGH	BYTE	S OF D					
22	FFFFFFFF	33CC55AA	33	CC	CC	0	F	1010	1100	0011	1111	1
STA	TE H: FORCE SA	A1 LOW. TWO L	OW BY	TES (OF D B	US SH						
23	FFFFFFF	33CC33CC	33	CC	CC	0	F	1010	1100	0011	1011	1
STA	TE G: FORCE -S							ALL BYTE	S.		4040	
24	FFFFFFF	ccccccc	33	CC			F	1010	1100	0011	1010	1
	TE F: FORCE -X									0011	1011	0
25	FFFFFFFF	5555555	CC	55	55	F	F	1010	1100	0011	1011	0

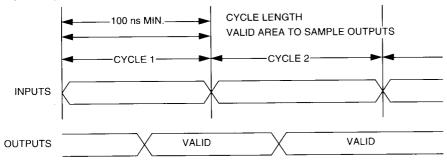


	OCK 3 -	Alas fallassia										
	state E and tests BUS (HI, LO)	the following: -CACHE (HI	, LO)		CPST	_WRC	(Hi, LC	D) -R	AMW (LO)	-	DEN (HI)	
V	M	D	S	S	Χ	P	L	C		H	-SS-	_
Ε	D	:	D	D	D	А	В	THCP	PMLL	LDRB	RADS	Χ
С	:	:	Н	L	:	R	Ε	RIAS	ADAA	DEAR	O1LD	D
\mathbf{T}	:	:	:	:	:	:	:	IDCT	RLTT	ANMD	M:HS	R
0	:	:	:	:	:	:	:	:RH_	EALH	::WR	C:/W	Ε
R	:	:	:	:	:	:	:	:IEW	RTOI	:::A	S:-A	А
	:	:	:	:	:	:	:	:V:R	R:::	:::M	::HP	D
#	:	:	:	:	:	:	:	:E:C	0:::	::::	::L:	:
	 	:	Ħ	Ė٦	:[: []	:□	::::	R:::	::::	::::	:
		BUS AND PAR		3 .								
26	5555555	5555555	00	00	00	F	F	1010	1111	0100	1011	1
27	AAAAAAA	AAAAAAA	00	00	00	F	F	1010	1111	0100	1011	1
28	ABAAAAA	ABAAAAA	00	00	00	7	F	1010	1111	0100	1011	1
29	ABABAAAA	ABABAAAA	00	00	00	3	F	1010	1111	0100	1011	1
		T_WRC AND -C	ACHE F	PINS.								
30	uuuuuuu	ABABABAA	00	00	00	u	F	1000	1111	0100	1011	1
		ST_WRC TO CLC	OCK IN	DATA	ON D	BUS.						
31	ABABABAA	ABABABAA	00	00	00	1	F	1001	1111	0100	1011	1
		PST_WRC LOW,			BUS, S		OF D B	US SHOU	LD NOT A	PPEAR O	N MD BUS	i.
32	ABABABAA	ABABABAB	00	00	00	1	F	1000	1111	0100	1011	1
		ST_WRC AGAIN		E NEV	V DAT	A ON N	ID BUS	3.				
33	ABABABAB	ABABABAB	00	00	00	0	F	1001	1111	0100	1011	1
34	AAAAAAA	AAAAAAA	00	00	00	F	F	1011	1111	0100	1011	1
	OCK 4 -											
Uses	state N and tests	s the following:	HL	DA (F	H)							
V	M	D	S	S	Χ	P	L	C		H	-SS-	_
Ε	D	:	D	D	D	А	В	THCP	PMLL	LDRB	RADS	Χ
С	:	:	Н	L	:	R	Ε	RIAS	ADAA	DEAR	O1LD	D
\mathbf{T}	:	:	:	:	:	:	:	IDCT	RLTT	ANMD	M:HS	R
0	:	:	:	:	:	:	:	:RH_	EALH	::WR	C:/W	Ε
R	:	:	:	:	:	:	:	:IEW	RTOI	:::A	S:-A	А
	:	:	:	:	:	:	:	:V:R	R:::	:::M	::HP	D
#	:	:	:	:	:	:	:	:E:C	0:::	::::	::L:	:
		· :		П	:□	:□	:□	::::	R:::	::::	::::	:
		L BUS AND SDH		_								
35	FFFFFFFF	FFFFFFFF	55	55	55	F	F	1011	1111	1111	1001	0
36	FFFFFFFF	FFFFFFF	AA	AA	AA	F	F	1011	1111	1111	1010	0



TEST PATTERN TIMING CONSTRAINTS

The patterns should be applied with a vector period of 100 ns. or more, with all inputs driven at the start of the cycle and all outputs sampled 60 ns or more after the beginning of the cycle, but at least 10 ns before the end of the cycle.



SPECIAL CASE SIGNALS

The only pins not tested with the test vectors described below are -TRI (low) and -HIDRIVE (high, low). The best way to test these is as follows.

-TRI (low):

Force –XDREAD high and –TRI low. If the XD bus is high impedance then –TRI (low) works correctly.

-HIDRIVE (high, low):

Set a current source in the range of 10 to 15 mA on one of the SD bus pins. Use a pattern that will drive a low onto the SD bus pin in question. Put a high value on the HIDRIVE pin and test the VOL value on that SD bus pin. Then change the-HIDRIVE pin to a low. The VOL value on the SD bus pin should drop by at least 100.0 mV.

The first group of signals shown below are the buses:

- MD.
- D.
- SDH (SD high byte).
- SDL (SD low byte).
- XD.
- PAR, and
- LBE.

All these buses are shown in hexadecimal format. The next group of signals are all the individual inputs and the —PARERROR output. These signals are shown in binary format. The last group of signals, starting after —SDSWAP, are the Output Enable signals for the bidirectional buses. The two 32-bit buses have an Output Enable for each byte, but all four Output Enable (OE) signals for a given bus will

transition together. The PAR bus uses the same Output Enable signals as the MD bus. All output enables are active low indicating that the VL82C332 is driving the bus anytime the Output Enable signal is low.

The values on the bidirectional buses indicate what is to be driven in if the corresponding OE signal is high, or what to sample on the outputs when the OE signal is low. A value of "u" indicates an output that is still "unknown".



AC CHARACTERISTICS: TA = 0°C to +70 °C, VDD = 5 V $\pm 5\%$, VSS = 0 V

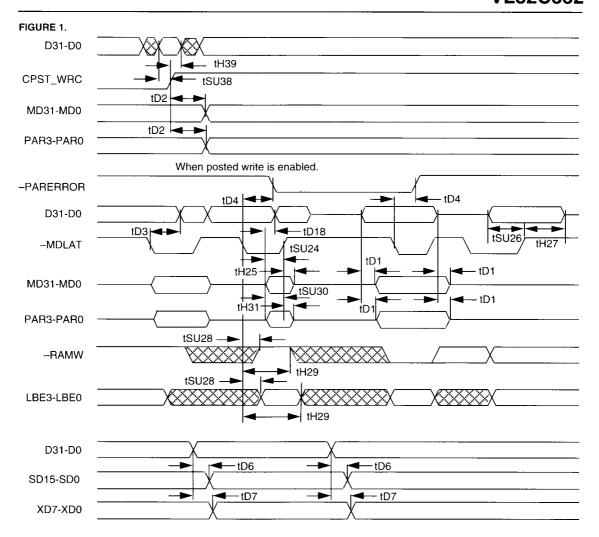
Symbol	Parameter	Min	Max	Unit	Conditions
tD1	D31-D0 to MD31-MD0, PAR3-PAR0 Delay	3	20	ns	CL=50 pF
tD2	CPST_WRC to MD31-MD0, PAR3-PAR0 Delay	3	27	ns	CL=50 pF
tD3	-MDLAT Low to D31-D0 Delay	3	25	ns	CL=50 pF
tD4	-MDLAT Low to -PARERROR	3	25	ns	CL=50 pF
tD5	-LATLO, -LATHI Low to D31-D0 Delay	3	25	ns	CL=50 pF
tD6	D31-D0 to XD7-XD0 Delay	3	35	ns	CL=50 pF
tD7	D31-D0 to SD15-SD0 Delay	3	30	ns	CL=200 pF Note 1
tD8	XD7-XD0 to MD31-MD0, PAR3-PAR0 Delay	3	25	ns	CL=50 pF
tD9	XD7-XD0 to D31-D0 Delay	3	25	ns	CL=50 pF
tD10	XD7-XD0 to SD15-SD0 Delay	3	30	ns	CL=200 pF Note 1
tD11	SD15-SD0 to XD7-XD0 Delay	3	35	ns	CL=50 pF
tD12	SD15-SD0 to MD31-MD0, PAR3-PAR0 Delay	3	25	ns	CL=50 pF
<u>tD</u> 13	SD15-SD0 to D31-D0 Delay	3	25	ns	CL=50 pF
tD14	SD15-SD8 to SD7-SD0 Delay	3	30	ns	CL=200 pF Note 1
tD15	SD7-SD0 to SD15-SD8 Delay	3	30	ns	CL=200 pF Note 1
tD16	MD31-MD0 to XD7-XD0 Delay	3	35	ns	CL=50 pF
tD17	MD31-MD0 to SD15-SD0 Delay	3	22	ns	CL=200 pF Note 1
tD18	MD31-MD0 to D31-D0 Delay	3	20	ns	CL=50 pF
tD19	MD15-MD0 to D31-D0 Delay	3	25	ns	CL=50 pF
tD20	CONTROL to SD15-SD0 Delay	3	35	ns	CL=200 pF Note 1
tD21	CONTROL to XD7-XD0 Delay	3	25	ns	CL=50 pF
tD22	CONTROL to MD31-MD0 Delay	3	20	ns	CL=50 pF
tD23	CONTROL to D31-D0 Delay	3	20	ns	CL=50 pF
tSU24	MD31-MD0 to -MDLAT Setup Time	3		ns	
tH25	MD31-MD0 from –MDLAT Hold Time	4		ns	
tSU26	D31-D0 to -MDLAT Setup Time	3		ns	
tH27	D31-D0 from –MDLAT Hold Time	4		ns	
tSU28	LBE3-LBE0, -RAMW to -MDLAT Setup Time	-1		ns	
tH29	LBE3-LBE0, -RAMW from -MDLAT Hold TIme	10		ns	
tSU30	PAR3-PAR0 toMDLAT Setup Time	3		ns	
tH31	PAR3-PAR0 from –MDLAT Hold Time	4		ns	
tSU32_	MD15-MD0 to -LATLO, -LATHI Setup Time	10		ns	
tH33	MD15-MD0 from –LATLO, –LATHI Hold Time	2		ns	
tSU34_	SD15-SD0 to -LATLO, -LATHI Setup Time	10	20	ns	

AC CHARACTERISTICS (Cont.): TA = 0°C to +70 °C, VDD = 5 V \pm 5%, VSS = 0 V

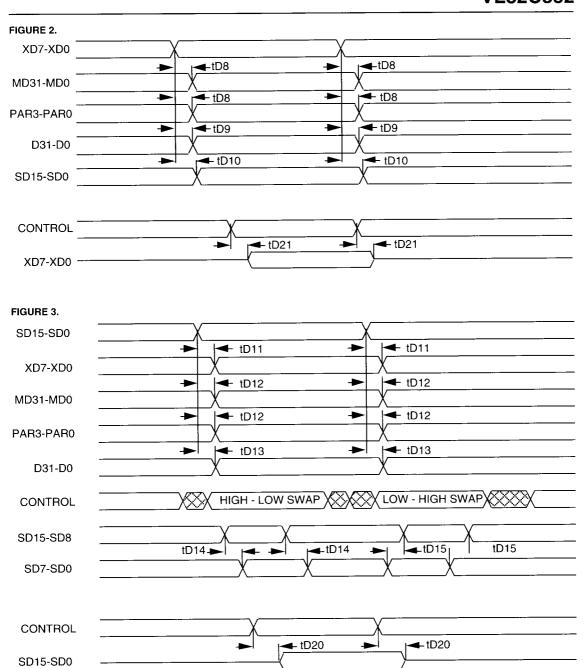
Symbol	Parameter	Min	Max	Unit	Conditions
tH35	SD15-SD0 from -LATLO, -LATHI Hold Time	2		ns	
tSU36	XD7-XD0 to -LATLO, -LATHI Setup Time	10		ns	_
tH37	XD7-XD0 from -LATLO, -LATHI Hold Time	2		ns	
tSU38	D31-D0 to CPST_WRC Setup Time	5		ns	
tH39	D31-D0 from CPST_WRC Hold Time	5		ns	
t40	-MDLAT Pulse Width	10		ns _	
t41	-LATLO, -LATHI Pulse Width	15		ns	
t42	CPST_WRC Pulse Width	15		ns	

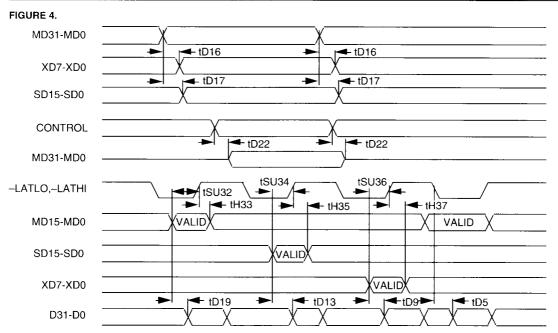
Note 1: These specifications are with -HIDRIVE active.











Note: tD5 is shown with data being sourced from the MD bus. This could also be the SD or XD buses.

ADVANCE INFORMATION

VL82C332

ABSOLUTE MAXIMUM RATINGS

Ambient Operating Temperature -10°C to +70°C

Storage Temperature -65°C to +150°C

Supply Voltage

-0.5 V to 7.0 V

to Ground

Applied Output -0.5 V to VDD + 0.3 V

Voltage

-0.5 V to VDD + 0.3 V

Applied Input Voltage

Power Dissipation

500 mW

Stresses above those listed may cause permanent damage to the device.

These are stress ratings only. Functional operation of this device at these or any other conditions above those

indicated in this data sheet is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

DC CHARACTERISTICS: TA = 0° C TO +70°C, VDD = 5 V ±5%, VSS = 0 V

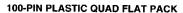
Symbol	Parameter	Min.	Max.	Unit	Conditions
VIL	Input Low Voltage	-0.5	0.8	V	
VIH	Input High Voltage	2.0	VDD	V	
VOL	Output Low Voltage		0.45	٧	
VOH	Output High Voltage	2.4		V	
IDD	Static Current		500	μА	
IDD	Dynamic Current		1.5	mA/MHz	Frequency is data dependant
IIL	Input Leakage		±10	μΑ	
IOZ	Three-state Leakage		±20	μΑ	

SEATING PLANE

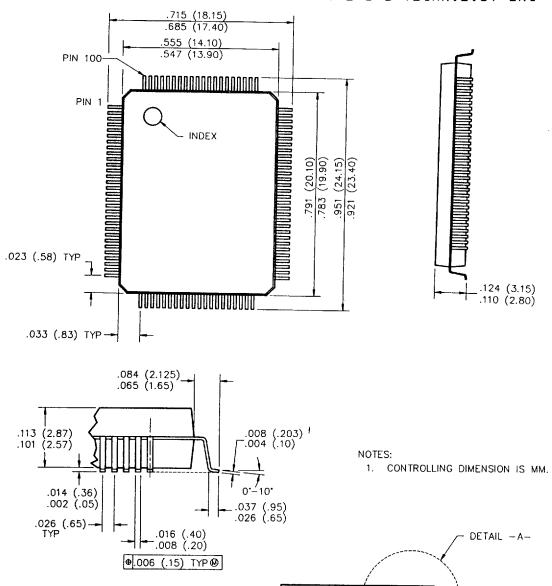


47E D = 9388347 0006780 7 WVTI

PACKAGE OUTLINES



V L S I TECHNOLOGY INC

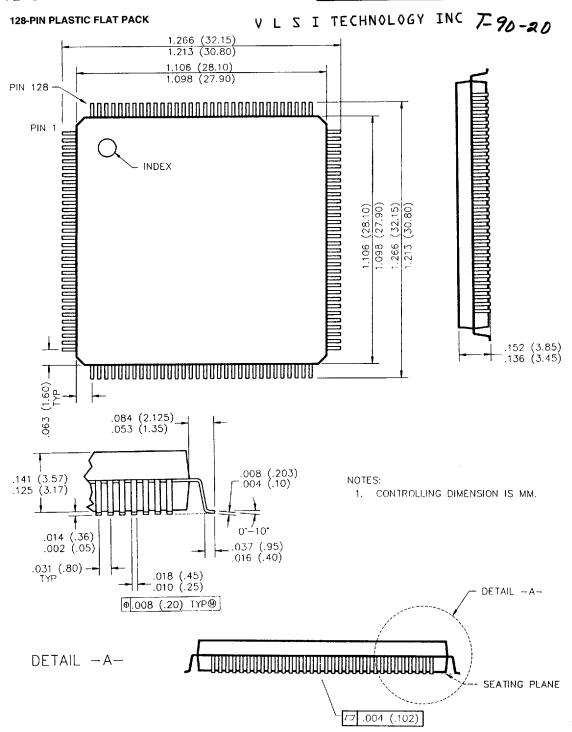


DETAIL -A-

.004 (.102)

47E D = 9388347 0006781 9 = VTI

PACKAGE OUTLINES



9388347 0006782 0 WVTI

PACKAGE OUTLINES

